

Substitute for Form 1449 A & B/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>		Application Number	10/659,436
		Confirmation Number	4091
		Filing Date	September 11, 2003
		First Named Inventor	Toshiyuki NOMURA
		Art Unit	2878
		Examiner Name	Not Yet Assigned
Sheet	1	of	1
		Attorney Docket Number	Q77464

U.S. PATENT DOCUMENTS					
Examiner Initials ^a	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US 6,341,257	B1	01-22-2002	HAALAND
		US 3,610,398	A	03-11-1997	ANDERSON et al.
		US 2001/0045521	A1	11-29-2001	PROZZO et al.
		US 5,750,994	A	05-12-1998	SCHLAGER
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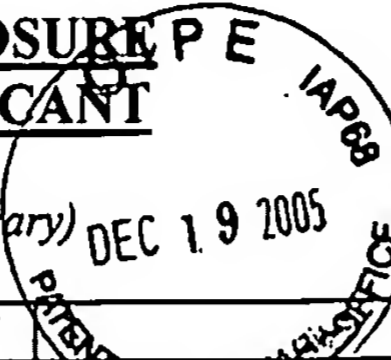
FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ³ (if known)			

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
		HAALAND, D. M. et al., "APPLICATION OF NEW LEAST-SQUARES METHODS FOR THE QUANTITATIVE INFRARED ANALYSIS OF MULTICOMPONENT SAMPLES" APPLIED SPECTROSCOPY, THE SOCIETY FOR APPLIED SPECTROSCOPY, Baltimore, US, vol. 36, no. 6, 1 November 1982, pp. 665-673, XP000676150	
LH		SMALL, G. W., "Application of digital filtering and pattern recognition techniques to interferogram-based Fourier transform infrared qualitative analysis", CHEMOMETRICS AND INTELLIGENT LABORATORY SYSTEMS, vol. 15, pages 203-217, XP009027005 (1992)	
		BERTRAN, E. et al., "Handling intrinsic non-linearity in near-infrared reflectance spectroscopy", CHEMOMETRICS AND INTELLIGENT LABORATORY SYSTEMS, ELSEVIER SCIENCE PUBLISHERS B.V. AMSTERDAM, NL, vol. 49, no. 2, 4 October 1999, pages 215-224, XP004255977	

Examiner Signature	CONSTANTINE HANNAHER	Date Considered	JAN 6 2006
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		US			
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		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
CH		JP	10-510180	A	10-06-1998	OPTISCAN, INC	Corresponds to WO 96/17546
CH		JP	2001-517791	A	10-09-2001	CHIRON DIAGNOSTIC CORP	Corresponds to WO/9915880
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